


<b>Search Notes</b>  	<b>Application/Control No.</b>  10769786	<b>Applicant(s)/Patent Under Reexamination</b>  CHOI ET AL.
	<b>Examiner</b>  Nguyen, Jennifer T	<b>Art Unit</b>  2629

SEARCHED			
Class	Subclass	Date	Examiner
345	60-72,88-104	8/19/07	JN

SEARCH NOTES		
Search Notes	Date	Examiner
east, IEEE, JPO	8/19/07	JN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
315	169.1,169.4	8/19/07	JN